Session 11: Solid State Physics

Bipolar Junction Transistor

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	2.	
Outline	3.	
	4.	
	5.	



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Introduction	3.	
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In recent decades, the higher layout density and low-power advantage of CMOS technology has eroded the BJT's dominance in integratedcircuit products.

(higher circuit density \rightarrow better system performance)

BJTs are still preferred in some integrated circuit applications because of their high speed and superior intrinsic gain.

- ✓ faster circuit speed
- **×** larger power dissipation

 \rightarrow limits device density (~10⁴ transistors/chip)

Si (npn, pnp) \rightarrow SiGe HBT \rightarrow GaAs (InSb) HBT

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	2. 3. 4. 5.

The BJT is a 3-terminal device, with two types: PNP and NPN



Review: Current Flow in a	1. I 2.	
Reverse-Biased pn Junction	3. 4. 5.	

- In a reverse-biased pn junction, there is negligible diffusion of majority carriers across the junction. The reverse saturation current is due to drift of minority carriers across the junction and depends on the rate of minority-carrier generation close to the junction (within ~one diffusion length of the depletion region).
 - ⇒ We can increase this reverse current by increasing the rate of minority-carrier generation, *e.g.* by
 - > optical excitation of carriers (*e.g.* photodiode)
 - electrical injection of minority carriers into the vicinity of the junction...

PNP BJT Operation	(Qualitative)
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A forward-biased "emitter" pn junction is used to inject minority carriers into the vicinity of a reverse-biased "collector" pn junction.

ightarrow The collector current is controlled via the base-emitter junction



To achieve high current gain:

- The injected minority carriers should not recombine within the quasi-neutral base region
- The emitter junction current is comprised almost entirely of carriers injected into the base (rather than carriers injected into the emitter)

Base Current Components	1. I 2.	
(Active Mode of Operation)	3. 4. 5.	

The base current consists of majority carriers supplied for

- 1. Recombination of injected minority carriers in the base
- 2. Injection of carriers into the emitter
- 3. Reverse saturation current in collector junction (Reduces $|I_B|$)
- 4. Recombination in the base-emitter depletion region





Output Characteristics for Common-Emitter Configuration





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Under normal operating conditions, the BJT may be viewed electrostatically as two independent pn junctions

BJT Electrostatics



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Under normal operating conditions, the BJT may be viewed electrostatically as two independent pn junctions





BJT Performance Parameters (PNP)



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Collector Current (PNP)

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Assumptions:

- 1) 1-D structure
- 2) $W \ll L_P$ and is constant
- 3) Like diode gen-rec in depletion region is negligible
- 4) Uniform doping + step junction
- 5) Low-level injection everywhere!



minority-carrier diffusion equation (different set of B.C. for each region) minority-carrier diffusion currents at depletion region edges



















	Quasi-Ideal BJT!	1. I 2. 3. 4. 5.	
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$$I_{B} = qA \left[\frac{D_{B}n_{E0}}{L_{E} \sim 25\mu} + \frac{Wp_{B0}}{2\tau_{B}} \right] \left(e^{\frac{qV_{EB}}{kT}} - 1 \right) + qA \left[\frac{D_{C}n_{C0}}{L_{C}} + \frac{Wp_{B0}}{2\tau_{B}} \right] \left(e^{\frac{qV_{CB}}{kT}} - 1 \right)$$

$$5 - 4 \times 10^{5} - 7.5 \times 10^{5} 4$$

$$I_{C} = qA \left[\frac{D_{B}p_{B0}}{\underbrace{W}} - \frac{Wp_{B0}}{\underbrace{2\tau_{B}}} \right] \left(e^{\frac{qV_{EB}}{kT}} - 1 \right) - qA \left[\frac{D_{C}n_{C0}}{L_{C}} + \frac{Wp_{B0}}{2\tau_{B}} \right] \left(e^{\frac{qV_{CB}}{kT}} - 1 \right)$$

~7 × 10⁸ ~7.5 × 10⁵

Hence:
$$\begin{cases} I_E \cong I_{Eideal} \\ I_C \cong I_{Cideal} \\ I_B \cong I_{Bideal} + I_{B2} \end{cases}$$



Determined by n_{C0} as $n_{C0} \gg p_{B0}$

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ICEO and ICBO	2.	
	3.	
	4.	
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 $I_{CEO} \gg I_{CBO}$



$$I_{CEO} = I_{C_n} + I_{C_p} = I_{CBO} + \beta_{dc}I_{CBO}$$



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Ebers-Moll Equations	3.	
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$$\begin{cases} I_E = I_{ES} \left(e^{\frac{qV_{EB}}{kT}} - 1 \right) + \alpha_I I_{C_I} \\ I_C = \alpha_N I_E - I_{CS} \left(e^{\frac{qV_{CB}}{kT}} - 1 \right) \\ \end{cases}$$
$$\begin{cases} I_E = \alpha_I I_{C_I} + I_{EO} \left(e^{\frac{qV_{EB}}{kT}} - 1 \right) \\ I_C = \alpha_N I_E - I_{CO} \left(e^{\frac{qV_{CB}}{kT}} - 1 \right) \end{cases}$$



Charge Control Analysis

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3. 4. 5.





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Base Transient Time	2.	
	3.	
	4.	
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$$Q_B = qA \frac{W\Delta p_B(0)}{2}$$

$$I_{C} = -qAD_{B} \frac{\partial \Delta p_{B}}{\partial x} \Big|_{x=W}$$
$$= qAD_{B} \frac{\Delta p_{B}(0,t)}{W}$$
$$= qAD_{B} \frac{2Q_{B}}{qAW^{2}}$$
$$I_{C} = \frac{Q_{B}}{(W^{2}/2D_{B})} = \frac{Q_{B}}{\tau_{t}}$$

$$\tau_t = \frac{W^2}{2D_B}$$

	1. I	
Turn ON	2.	
	3.	
	4.	
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Turn-on:

$$i_{B} = \frac{V_{S}}{R_{S}} = I_{BB}$$

$$\frac{dQ_{B}}{dt} = I_{BB} - \frac{Q_{B}}{\tau_{B}} \rightarrow Q_{B}(t) = I_{BB}\tau_{B} + Ae^{-t/\tau_{B}}$$
I.C.:

$$Q_{B}(0) = 0 \rightarrow Q_{B}(t) = I_{BB}\tau_{B}\left(1 - e^{-t/\tau_{B}}\right)$$

$$\rightarrow \begin{cases} i_{C}(t) = \frac{Q_{B}(t)}{\tau_{t}} = \frac{I_{BB}\tau_{B}}{\tau_{t}}\left(1 - e^{-t/\tau_{B}}\right) & 0 < t \le t_{1} \\ i_{C}(t) = I_{CC} = \frac{V_{CC}}{R_{L}} \end{cases}$$

$$i_{C}(t_{r}) = I_{CC} \rightarrow t_{r} = \tau_{B}\ln\left(\frac{1}{1 - \frac{I_{CC}}{I_{BB}}\frac{\tau_{t}}{\tau_{B}}}\right)$$

	1. I	
Turn OFF	2.	
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Turn-off:

$$\frac{dQ_B}{dt} = -kI_{BB} - \frac{Q_B}{\tau_B} \longrightarrow Q_B(t) = -kI_{BB}\tau_B + Ae^{-t/\tau_B}$$

$$|.C.: \quad Q_B(0)\Big|_{turnOFF} = Q_B(\infty)\Big|_{turnON} = I_{BB}\tau_B$$

$$\rightarrow Q_B(t) = I_{BB}\tau_B\left((1+k)e^{-t/\tau_B} - k\right)$$

$$\rightarrow \begin{cases} i_C(t) = I_{CC} & t_3 < t \le t_4 \\ i_C(t) = \frac{Q_B(t)}{\tau_t} = \frac{I_{BB}\tau_B}{\tau_t}\left((1+k)e^{-t/\tau_B} - k\right) & t > t_4 \end{cases}$$

$$t_{sd} = t_4 - t_3 \rightarrow t_{sd} = \tau_B \ln\left(\frac{1+k}{\frac{I_{CC}}{I_{BB}}\frac{\tau_t}{\tau_B} + k}\right)$$

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Non-Ideal BJ I	3.	
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Deviations from Ideality:

- 1. Base width modulation (Early effect)
- 2. Punch-through
- 3. Avalanche Breakdown
- 4. Geometrical effects
- 5. Generation-Recombination in depletion regions
- 6. High-level injection



$$\begin{split} I_{E} &\cong I_{E_{p}} = qA \frac{D_{B}p_{B0}}{W} e^{qV_{EB}/kT} & i_{C} \text{ Saturation} \\ V_{CB} &\nearrow W \searrow \rightarrow I_{E} &\nearrow \\ V_{CB} &\nearrow W \searrow \rightarrow I_{E} &\nearrow \\ -V_{A} \text{ Early voltage} & v_{CE} \\ \end{split}$$
Show that
HW: $V_{A} = \frac{qN_{B}W}{C_{jC}} \qquad Active: i_{C} = I_{S}e^{\frac{v_{BE}}{nV_{T}}}(1 + \frac{v_{CE}}{V_{A}}) \end{split}$



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Avalanche Breakdown	3.	
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$$BV_{CEO} = \frac{1}{\beta^{1/m}} BV_{CBO} \qquad m \sim 4$$





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G-R in Depl. Region , High-level injection	2.	
	3.	
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p-n-p Individual device



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Small-Signal Model	3.	
	4.	
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High Freq: $C_{j_{c}} = C_{\mu}$ $r_{o} = \frac{I_{c}}{V_{A}}$ $C_{j_{E}} = v_{\pi}^{+} + r_{\pi} + C_{\pi}$ $F_{o} = \frac{C_{\mu 0}}{\left(1 - \frac{V_{CB}}{V_{CB0}}\right)^{m}}$

